

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of )

Yehiel Gotkis )

Application No. 10/810,209 )

Filed: March 26, 2004 )



Examiner: Unassigned )

Art Unit: 1765 )

Docket No. LAM2P466 )

Date: September 20, 2004 )

For: METHOD AND APPARATUS FOR  
MEASUREMENT OF THIN FILMS AND  
RESIDUES ON SEMICONDUCTOR  
SYBSTRATES

## CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail to: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450 on September 20, 2004.

Signed: \_\_\_\_\_

  
Kay Harlow

Mail Stop: Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Transmitted herewith is an Amendment in the above-identified application.

The fee has been calculated as shown below.

	Claims Remaining After <u>Amendment</u>	Highest Previously <u>Paid For</u>	Present <u>Extra</u>	SMALL ENTITY <u>RATE FEE</u>	OR	LARGE ENTITY <u>RATE FEE</u>
TOTAL CLAIMS	_____ - _____	_____	_____	X09 = \$	OR	X18 = \$
INDEP CLAIMS	_____ - _____	_____	_____	X43 = \$	OR	X86 = \$
[ ] Multiple Dependent Claim Present and Fee Not Previously Paid				\$145		\$290
			TOTAL	\$ _____		\$ _____

- ☐ Applicant(s) hereby petition for a \_\_\_\_\_ month(s) extension of time to respond to the outstanding Office Action.
- ☒ Applicant(s) believe that no (additional) Extension of Time is required; however, if it is determined that such an extension is required, Applicant(s) hereby petition that such an extension be granted and authorize the Commissioner to charge the required fees for an Extension of Time under 37 CFR 1.136 to Deposit Account No. 50-0805.
- ☐ Enclosed is our Check No. \_\_\_\_\_ in the amount of \$\_\_\_\_\_ to cover the additional claim fee and/or extension of time fees.
- ☒ If the required fees are missing or any additional fees are required to facilitate filing the enclosed response, please charge such fees or credit any overpayment to Deposit Account No. 50-0805 (Order No.). A copy of this sheet is enclosed.

Respectfully submitted,  
MARTINE & PENILLA, LLP

  
Albert S. Penilla, Esq.  
Registration No. 39,487

710 Lakeway Drive, Suite 170  
Sunnyvale, CA 94085  
Telephone: (408) 749-6900  
Facsimile: (408) 749-6901  
Customer Number 25920



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PATENT

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Signed: \_\_\_\_\_

*Kay Harlow*  
Kay Harlow

AMENDMENT

Mail Stop: Amendment  
Honorable Commissioner for Patents  
Alexandria VA 22313-1450

Dear Sir:

Please enter this preliminary Amendment before examination.

Amendments to the Drawings begin on page 2 of this paper and include an attached replacement sheet.

Remarks/Arguments begin on page 3 of this paper.